

Search Notes

Applicant/Control No.

10/602,804

Examiner

Quynh H. Nguyen

Applicant(s)/Patent under
Re-examination

MCILWAINE ET AL.

Art Unit

2614

SEARCHED

Class	Subclass	Date	Examiner
379	265.01 265.02 265.05 266.07	6/7/06	QN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched: East, USPGPub, USPAT	6/7/06	QN
Inventor searched through PALM database	6/7/06	QN